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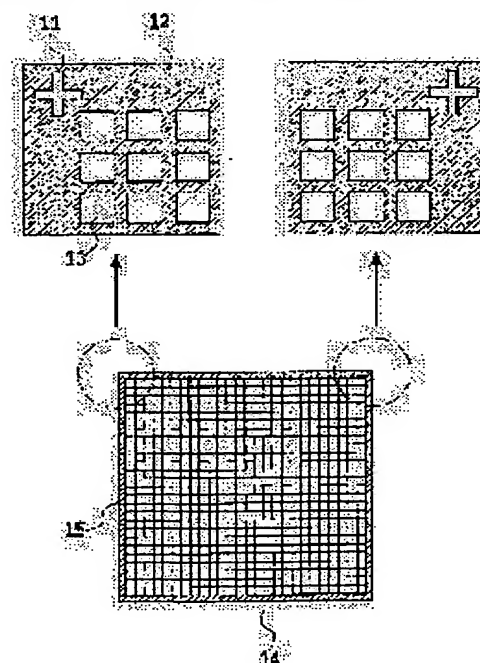
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(54) PROBE CARRIER, PROBE FIXING CARRIER, AND THEIR MANUFACTURING METHODS

(57)Abstract:

PROBLEM TO BE SOLVED: To accurately and quickly manufacture a probe carrier that is improved in reliability (particularly, is made free from mixed liquids and voids) and increased in density and to accurately and quickly detect the position of a target compound specifically coupled with a probe fixed on the probe carrier.

SOLUTION: A solution containing the probe is imparted to a specific position on the probe carrier having an index in a probe non-fixing area on the basis of the position of the index and the probe is fixed. Preferably, partition walls are formed on the carrier and the spreadability of the probe solution in the areas surrounded by the partition walls is improved by improving the water repellency of the partition walls by irradiating the walls with a plasma in a gas atmosphere containing fluorine atoms and then bringing water into contact with the carrier. In addition, the position of the target compound specifically coupled with the probe fixed on the probe carrier manufactured by the manufacturing method can be detected accurately and quickly on the basis of the index.



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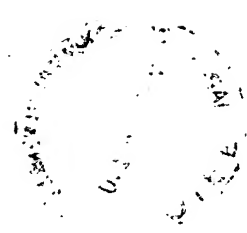
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